Se	arcn	note	S

Application/Control No.	Applicant(s)/Patent under Reexamination
10/705,404	MIZUTANI ET AL.
Examiner	Art Unit
Karin M. Reichle	3761

SEAR	CHED	
Subclass	Date	Examiner
	<u> </u>	SEARCHED Subclass Date

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH	TES STRATEGY)
	DATE	EXMR
consulted SPE wrt missing pages	6/7/2006	KMR